

Search Notes

Application/Control No.

10/511,792

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

RADENNE ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	678 - 681	2/16/2006	C.C.
235	492	2/16/2006	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	2/16/2006	C.C.